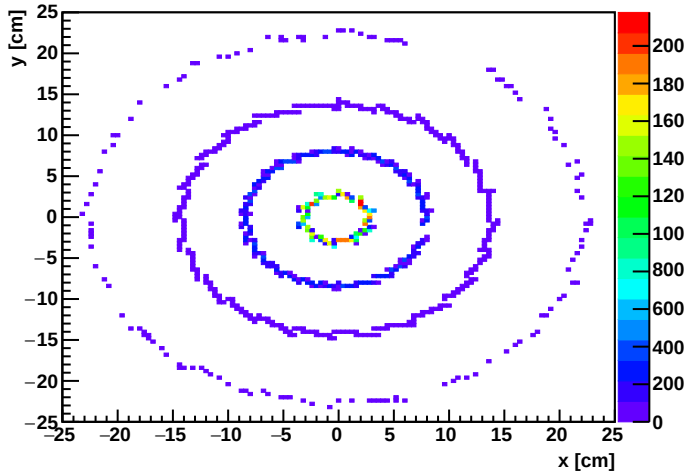
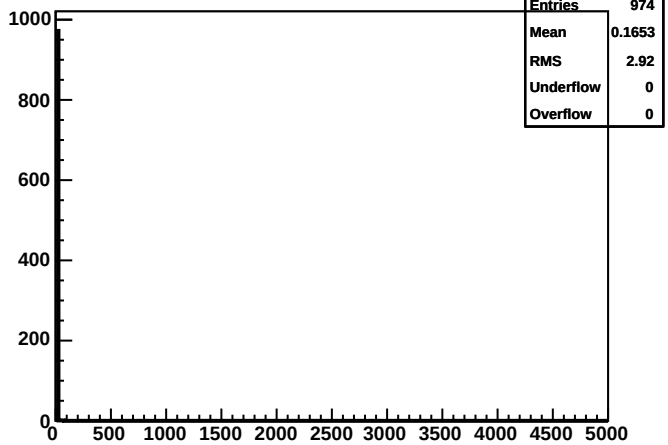
QA plots for pAu 200GeV run 2015 for SL15l library

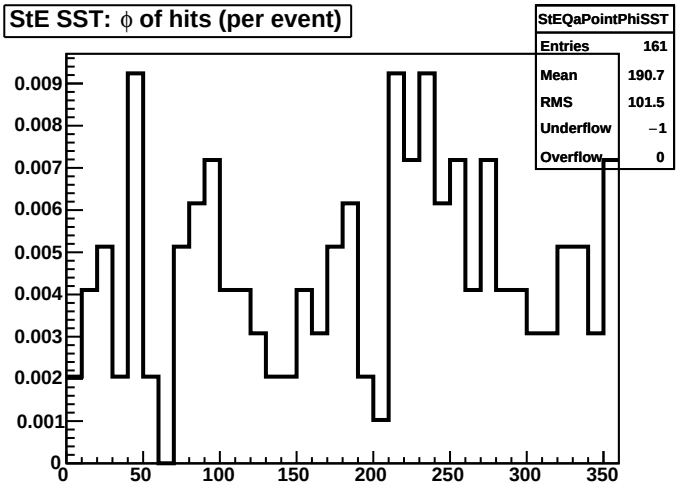
PIXEL, IST, SSD: Distribution of hits in XY



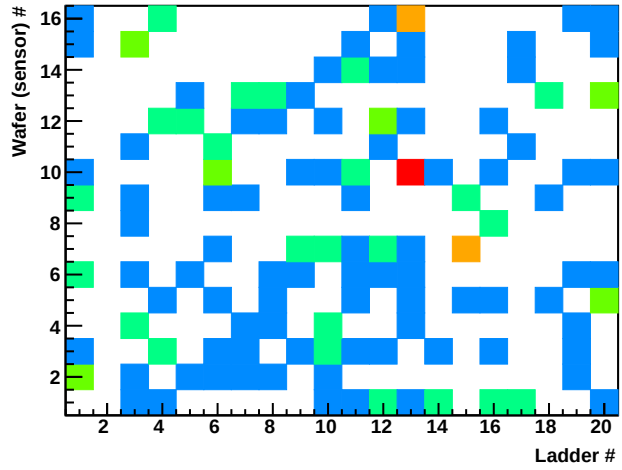
StE point: # hits sst



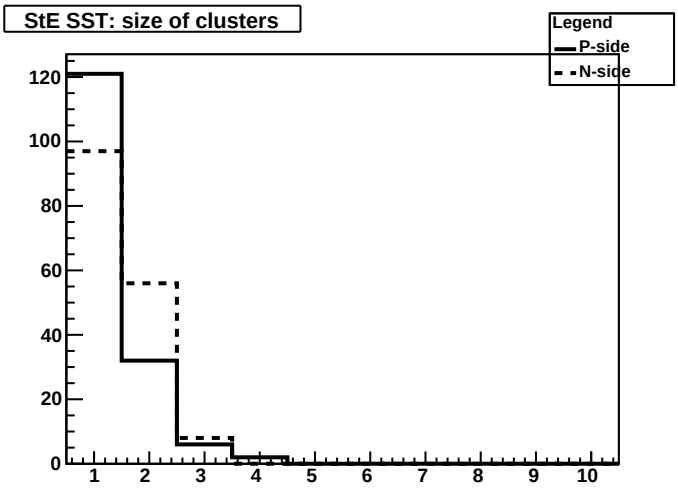
StE SST: ϕ of hits (per event)



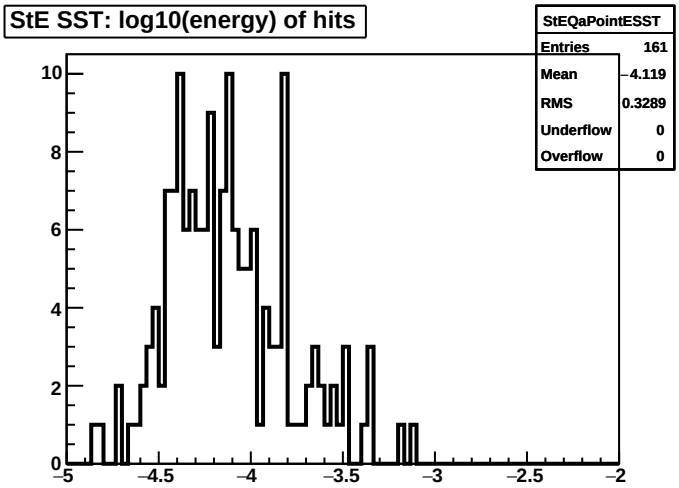
StE SST: wafer id vs ladder id (per event)



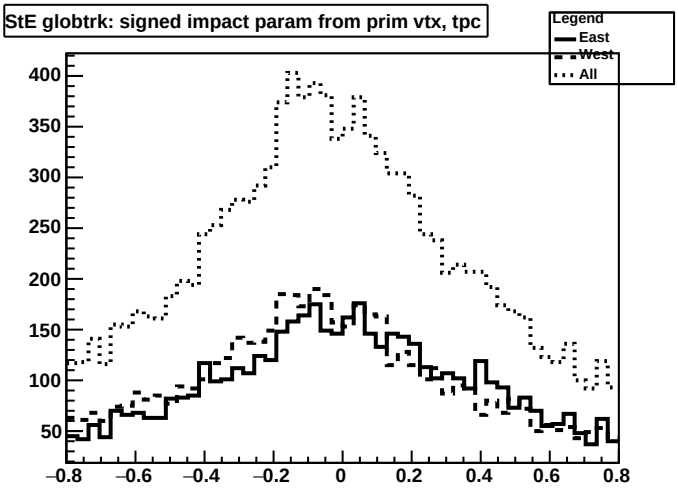
StE SST: size of clusters

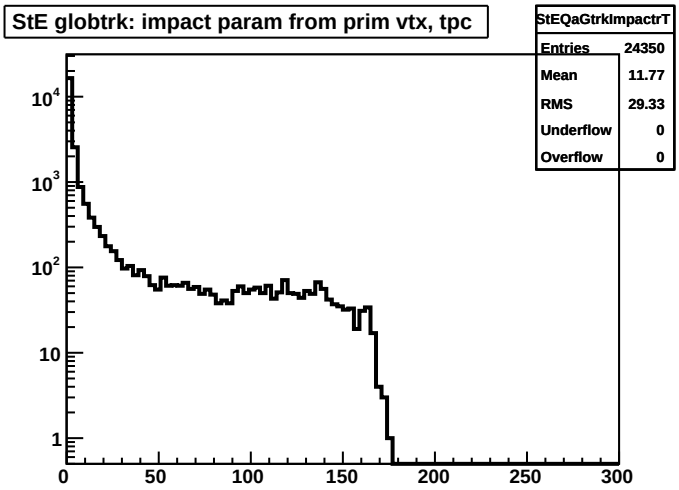


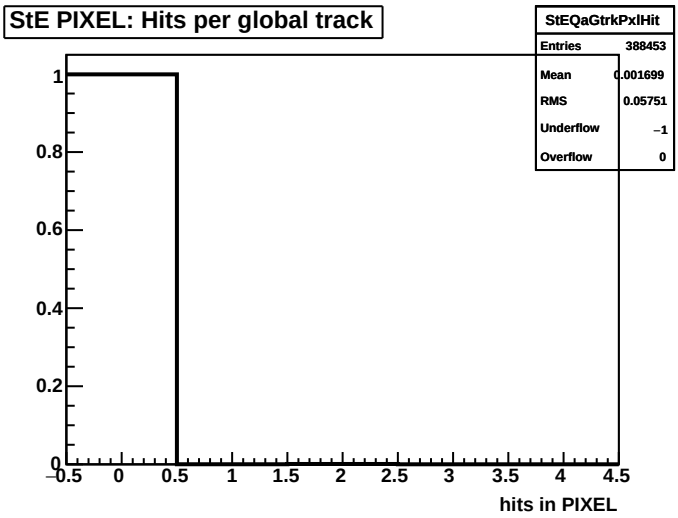
StE SST: log10(energy) of hits

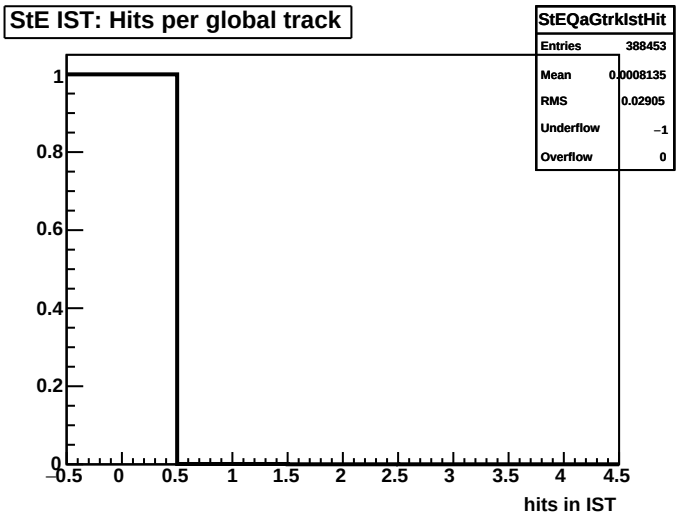


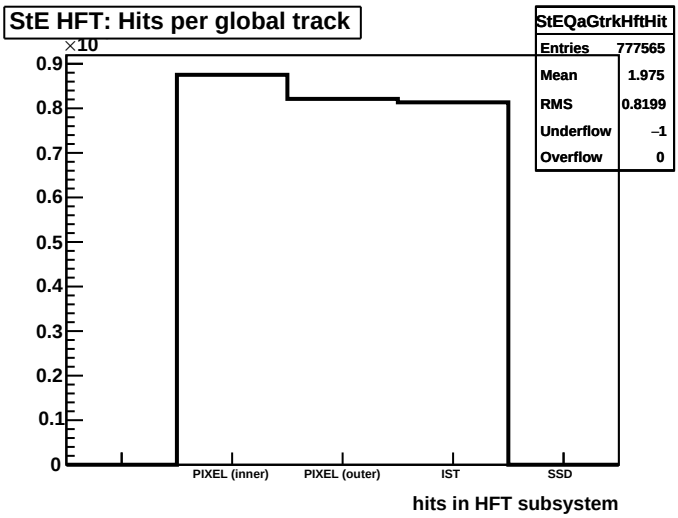
QA plots for pAu 200GeV run 2015 for SL15l library

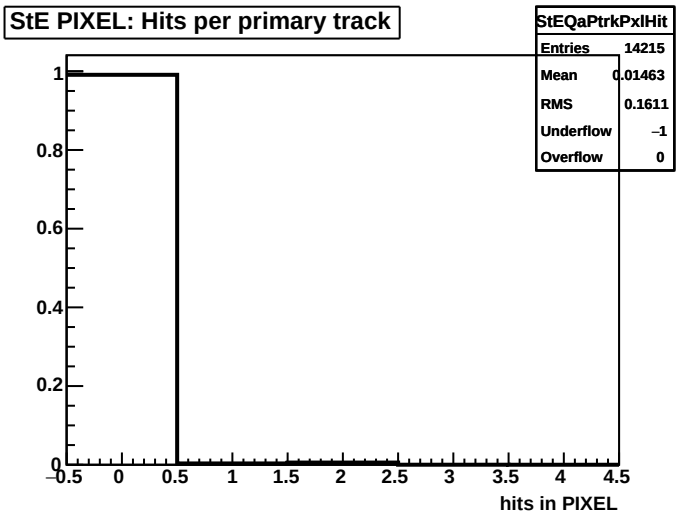






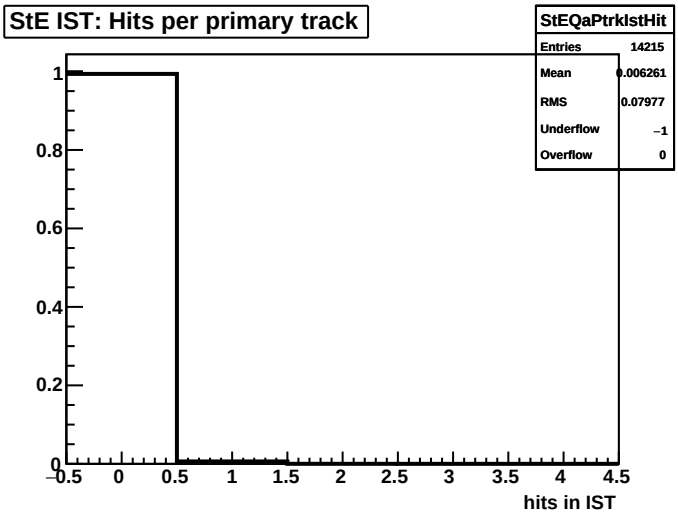




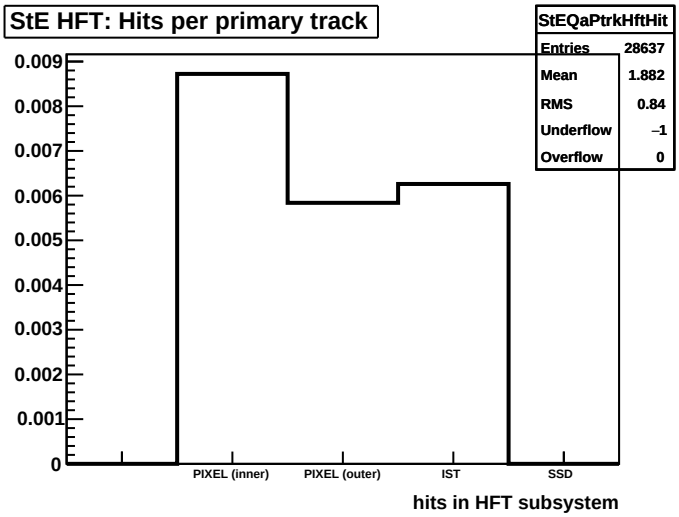


QA plots for pAu 200GeV run 2015 for SL15l library

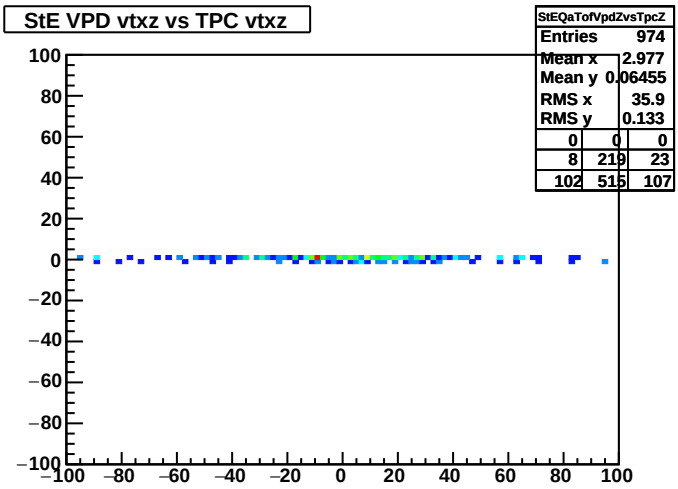
StE IST: Hits per primary track



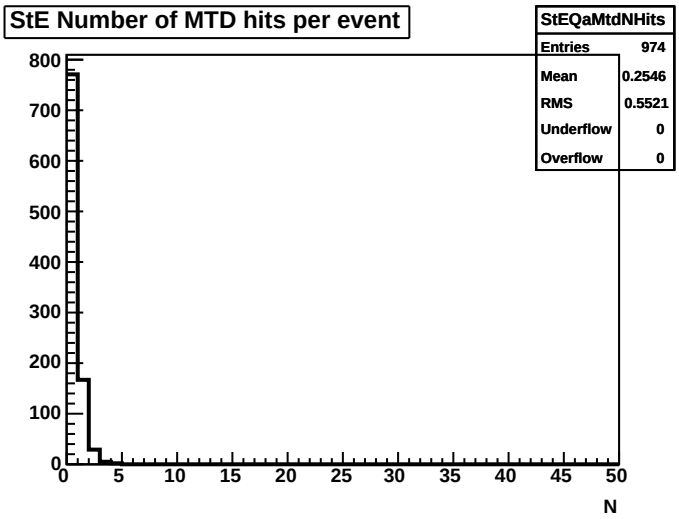
StE HFT: Hits per primary track



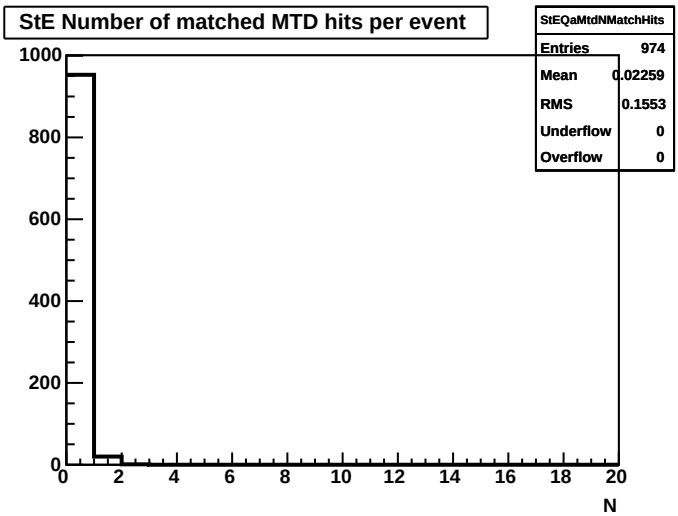
StE VPD vtxz vs TPC vtxz



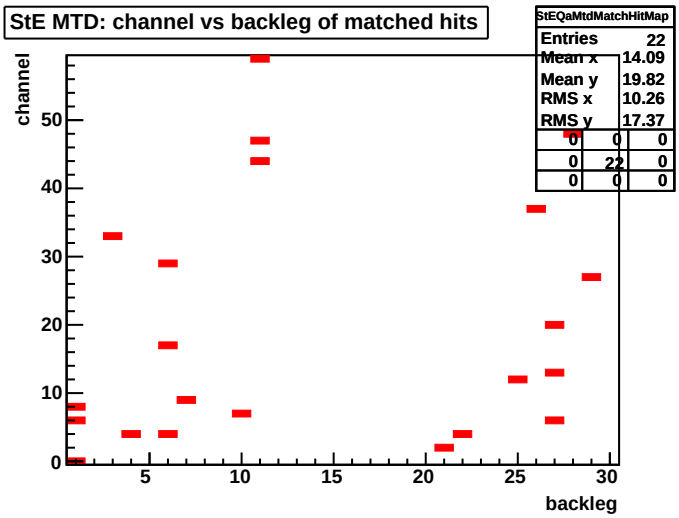
StE Number of MTD hits per event



StE Number of matched MTD hits per event

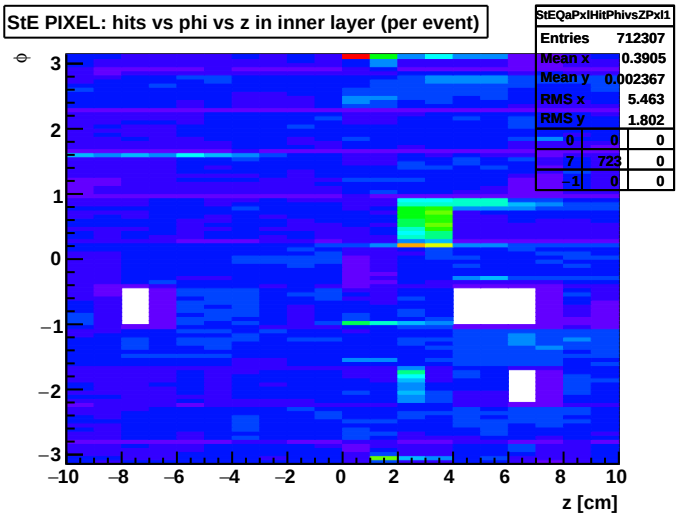


StE MTD: channel vs backleg of matched hits

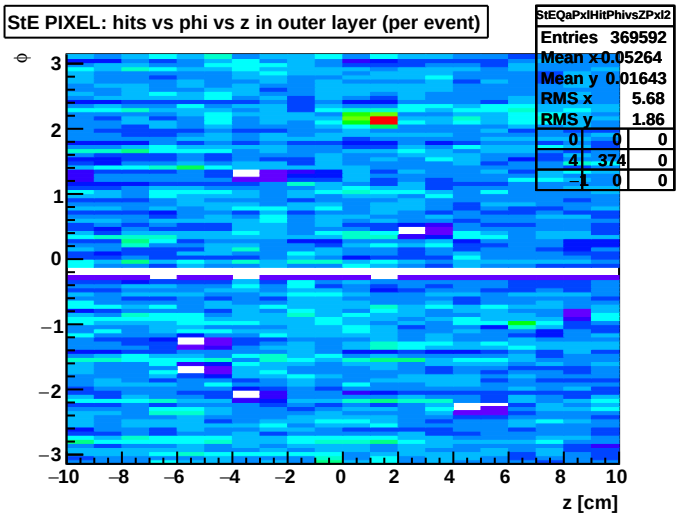


QA plots for pAu 200GeV run 2015 for SL15l library

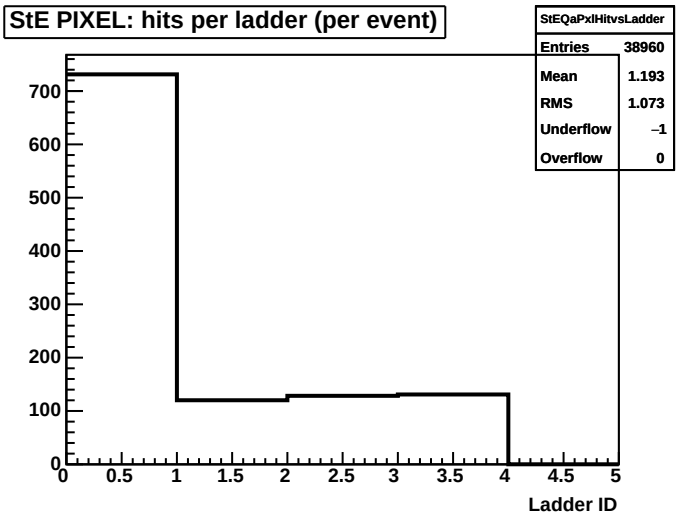
StE PIXEL: hits vs phi vs z in inner layer (per event)



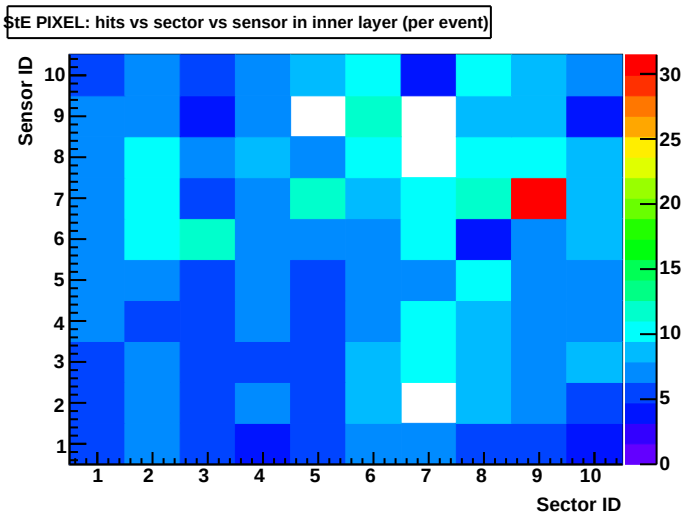
StE PIXEL: hits vs phi vs z in outer layer (per event)



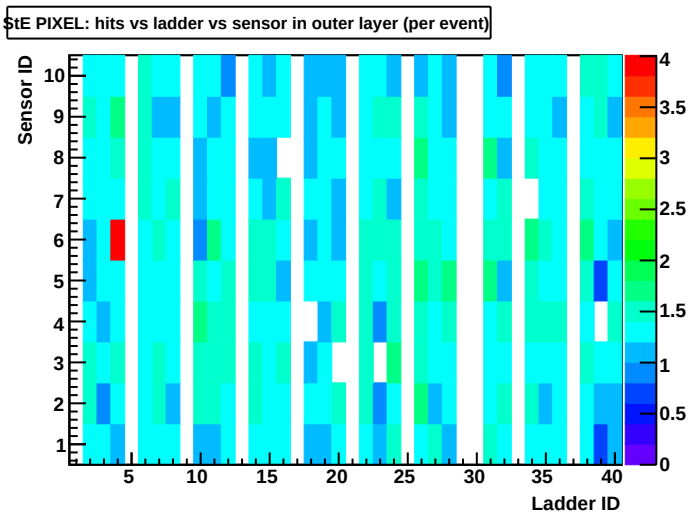
StE PIXEL: hits per ladder (per event)



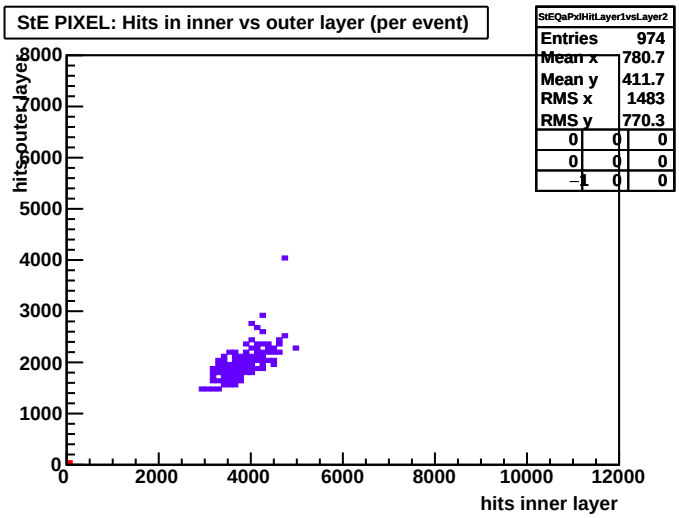
StE PIXEL: hits vs sector vs sensor in inner layer (per event)



StE PIXEL: hits vs ladder vs sensor in outer layer (per event)

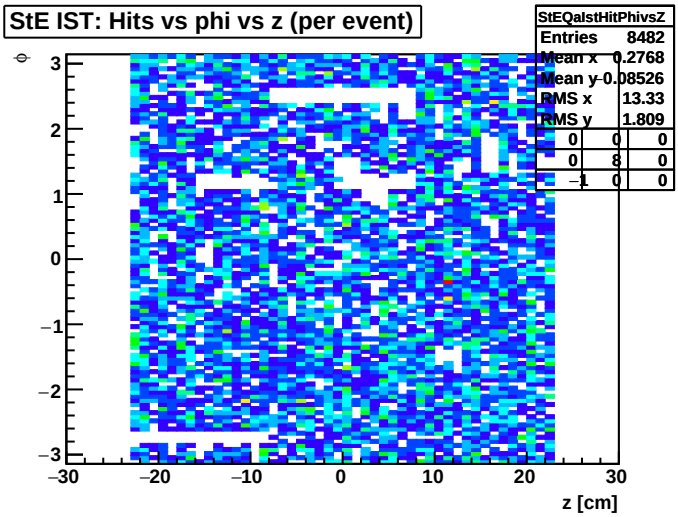


StE PIXEL: Hits in inner vs outer layer (per event)

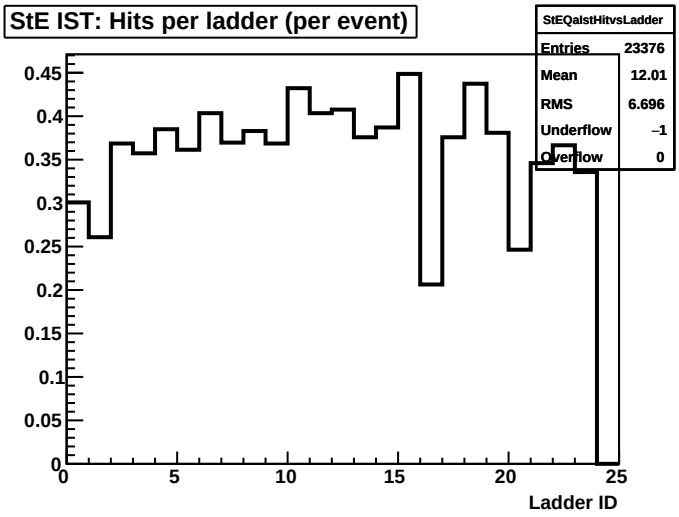


QA plots for pAu 200GeV run 2015 for SL15l library

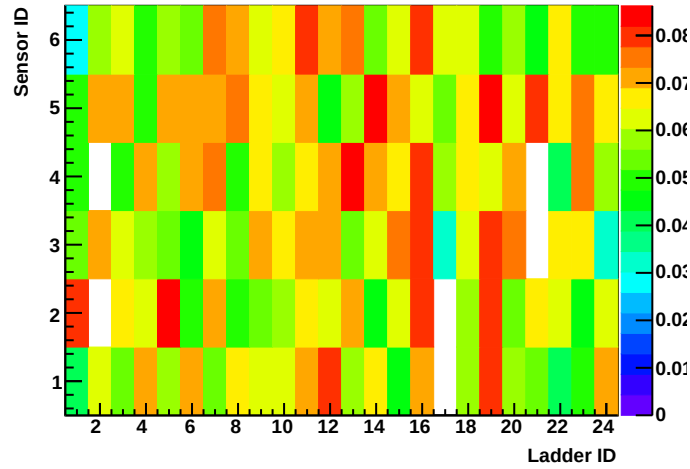
StE IST: Hits vs phi vs z (per event)



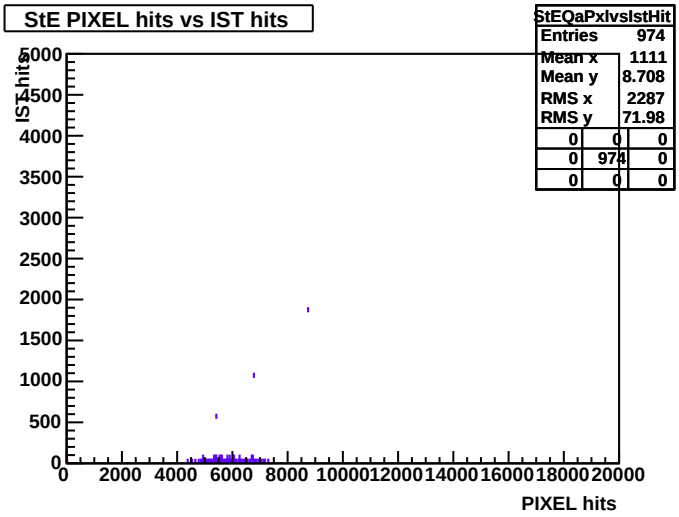
StE IST: Hits per ladder (per event)



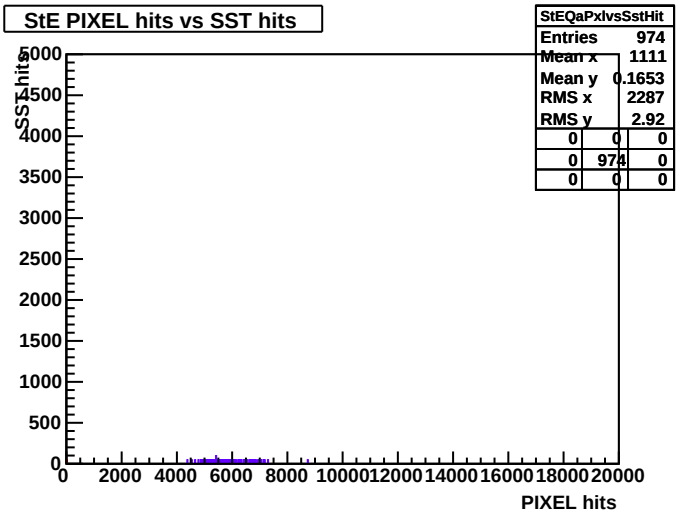
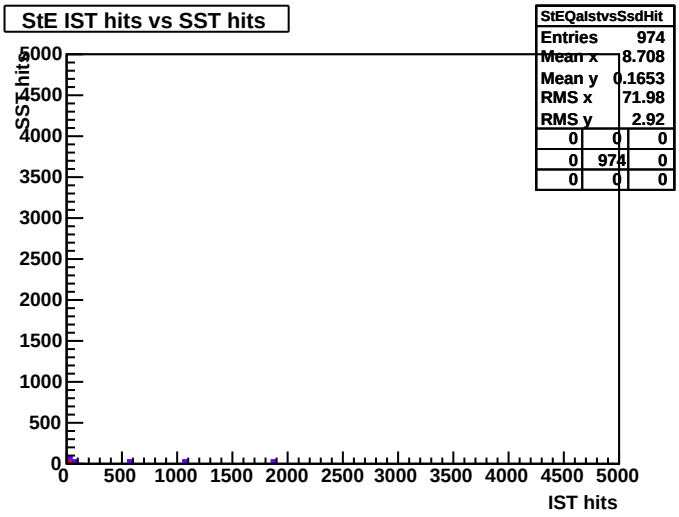
StE IST: Hits vs ladder vs sensor (per event)



StE PIXEL hits vs IST hits



StE PIXEL hits vs SST hits



StE IST hits vs SST hits